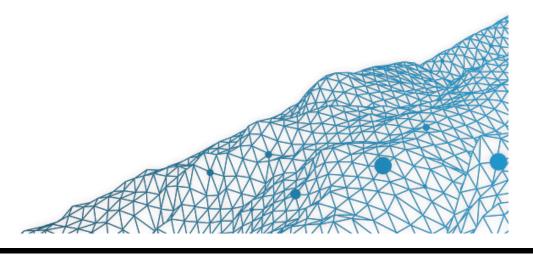
7 Classification & Goodness of Fit (Theoretical)

Arthur Charpentier (Université du Québec à Montréal)

Machine Learning & Econometrics

SIDE Summer School - July 2019



Assume that training and validation data are drawn i.i.d. from \mathbb{P} , or $(Y, \mathbf{X}) \sim F$ Consider $y \in \{-1, +1\}$. The true risk of a classifier is

$$\mathcal{R}(m) = \mathbb{P}_{(Y, \boldsymbol{X}) \sim F} \left(m(\boldsymbol{X}) \neq Y \right) = \mathbb{E}_{(Y, \boldsymbol{X}) \sim F} \left(\ell(m(\boldsymbol{X}), Y) \right)$$

Bayes classifier is

$$b(\boldsymbol{x}) = \operatorname{sign}\left(\mathbb{E}_{(Y, \boldsymbol{X}) \sim F}\left[Y | \boldsymbol{X} = \boldsymbol{x}\right]\right)$$

which satisfies $\mathcal{R}(b) = \inf_{m \in \mathcal{H}} \{\mathcal{R}(m)\}$ (in the class \mathcal{H} of all measurable functions), called Bayes risk.

The empirical risk is

$$\widehat{\mathcal{R}}_n(m) = \frac{1}{n} \sum_{i=1}^n \ell(y_i, m(\boldsymbol{x}_i))$$

One might think of using regularized empirical risk minimization,

$$\widehat{m}_n \in \underset{m \in \mathcal{M}}{\operatorname{argmin}} \left\{ \widehat{\mathcal{R}}_n(m) + \lambda ||m|| \right\}$$

in a class of models \mathcal{M} , where regularization term will control the complexity of the model to prevent overfitting.

Let m^* denote the best model in \mathcal{M} , $m^* = \underset{m \in \mathcal{M}}{\operatorname{argmin}} \{\mathcal{R}(m)\}$

$$\mathcal{R}(\widehat{m}_n) - \mathcal{R}(b) = \underbrace{\mathcal{R}(\widehat{m}_n) - \mathcal{R}(m^*)}_{\text{estimation error}} + \underbrace{\mathcal{R}(m^*) - \mathcal{R}(b)}_{\text{approximation error}}$$

Since
$$\mathcal{R}(\widehat{m}_n) = \widehat{\mathcal{R}}_n(\widehat{m}_n) + [\mathcal{R}(\widehat{m}_n) - \widehat{\mathcal{R}}_n(\widehat{m}_n)]$$
, we can write

$$\mathcal{R}(\widehat{m}_n) \leq \widehat{\mathcal{R}}_n(\widehat{m}_n) + \text{something}(m, \mathcal{M})$$

To quantify this something (m, \mathcal{F}) , we need Hoeffding inequality, see Hoeffding (1963, Probability inequalities for sums of bounded random variables)

Let $g(\boldsymbol{x}, y) = \ell(m(\boldsymbol{x}), y)$, for some model m. Let

$$\mathcal{G} = \{g : (\boldsymbol{x}, y) \mapsto \ell(m(\boldsymbol{x}), y), m \in \mathcal{M}\}$$

If
$$Z = (Y, \mathbf{X})$$
, set $\mathcal{R}(g) = \mathbb{E}_{Z \sim F}(g(Z))$ and $\widehat{\mathcal{R}}_n(g) = \frac{1}{n} \sum_{i=1}^n g(z_i)$.

Hoeffding inequality

If Z_1, \dots, Z_n are i.i.d. and if h is a bounded function (in [a, b]), then, $\forall \epsilon > 0$

$$\mathbb{P}_n\left[\left|\frac{1}{n}\sum_{i=1}^n h(Z_i) - \mathbb{E}_F[h(Z)]\right| \ge \epsilon\right] \le 2\exp\left(\frac{-2n\epsilon^2}{(b-a)^2}\right)$$

or equivalently (let δ denote the upper bound)

$$\mathbb{P}_n\left[\left|\frac{1}{n}\sum_{i=1}^n h(Z_i) - \mathbb{E}_F[h(Z)]\right| \ge (b-a)\sqrt{\frac{-1}{2n}\log(2\delta)}\right] \le \delta$$

We can actually derive a one side majoration, and with probability (at least) $1 - \delta$

$$\mathcal{R}(g) \le \widehat{\mathcal{R}}_n(g) + \sqrt{\frac{-1}{2n} \log \delta}$$

$$\mathcal{R}(m) - \widehat{\mathcal{R}}_n(m)$$

For a fixed
$$m \in \mathcal{M}$$
, $\mathcal{R}(m) - \widehat{\mathcal{R}}_n(m) \sim \frac{1}{\sqrt{n}}$

But it doesn't help much, we need uniform deviations (or worst deviation).

Consider a finite set of models. Define the set of bad samples

$$\mathcal{Z}_j = \left\{ (z_1, \cdots, z_n) : \mathcal{R}(g_j) - \widehat{\mathcal{R}}_n(g_j) \ge 0 \right\}$$

so that $\mathbb{P}[(Z_1, \dots, Z_n) \in \mathcal{Z}_j] \leq \delta$, and then

$$\mathbb{P}[(Z_1,\cdots,Z_n)\in\mathcal{Z}_1\cap\mathcal{Z}_1]\leq\mathbb{P}[(Z_1,\cdots,Z_n)\in\mathcal{Z}_1]+\mathbb{P}[(Z_1,\cdots,Z_n)\in\mathcal{Z}_2]\leq2\delta$$

so that

$$\mathbb{P}\left[(Z_1,\cdots,Z_n)\in\bigcap_{j=1}^{\nu}\mathcal{Z}_j\right]\leq \sum_{j=1}^{\nu}\mathbb{P}[(Z_1,\cdots,Z_n)\in\mathcal{Z}_j]\leq \nu\delta$$

Hence,

$$\mathbb{P}[\exists g \in \{g_1, \cdots, g_{\nu}\} : \mathcal{R}(g) - \widehat{\mathcal{R}}_n(g) \ge \epsilon] \le \nu \cdot \mathbb{P}[R(g) - \widehat{R}_n(g) \ge \epsilon] \le \nu \cdot \exp[-2n\epsilon^2]$$

If $\delta = \nu \exp[-2n\epsilon^2]$, we can write ϵ and with probability (at least) $1 - \delta$

$$\forall g \in \{g_1, \dots, g_{\nu}\}, \mathcal{R}(g) - \widehat{\mathcal{R}}_n(g) \leq \sqrt{\frac{1}{n}} (\log \nu - \log \delta)$$

Thus, we can write, for a finite set of models $\mathcal{M} = \{m_1, \dots, m_{\nu}\},\$

$$\forall m \in \{m_1, \cdots, m_{\nu}\}, \mathcal{R}(m) \leq \widehat{\mathcal{R}}_n(m) + \sqrt{\frac{1}{n}} (\log \nu - \log \delta)$$

$$\mathcal{R}(m) - \widehat{\mathcal{R}}_n(m)$$
 - \mathcal{M} finite, $u = |\mathcal{M}|$

For the worst case scenario

$$\sup_{m \in \mathcal{M}_{\nu}} \left\{ \mathcal{R}(m) - \widehat{\mathcal{R}}_n(m) \right\} \sim \frac{\log \nu}{\sqrt{n}}$$

Now, what if \mathcal{M} is infinite?

Write Hoeffding's inequality as

$$\mathbb{P}\left[\mathcal{R}(g) - \widehat{\mathcal{R}}_n(g) \ge \sqrt{\frac{-1}{2n}\log \delta_g}\right] \le \delta_g$$

so that, we a countable set \mathcal{G}

$$\mathbb{P}\left[\exists g \in \mathcal{G} : \mathcal{R}(g) - \widehat{\mathcal{R}}_n(g) \ge \sqrt{\frac{-1}{2n} \log \delta_g}\right] \le \sum_{g \in \mathcal{G}} \delta_g$$

If $\delta_g = \delta \cdot \mu(g)$ where μ is some measure on \mathcal{G} , with probability (at least) $1 - \delta$,

$$\forall g \in \mathcal{G}, \mathcal{R}(g) \leq \widehat{\mathcal{R}}_n(g) + \sqrt{\frac{-1}{2n}} [\log \delta + \log \mu(g)]$$

(see previous computations with $\mu(g) = \nu^{-1}$)

More generally, given a sample $z = \{z_1, \dots, z_n\}$, let \mathcal{M}_z denote the set of classification that can be obtained,

$$\mathcal{M}_{\boldsymbol{z}} = \{(m(z_1), \cdots, m(z_n))\}$$

The growth function is the maximum number of ways into which n points can be classified by the function class \mathcal{M}

$$G_{\mathcal{M}}(n) = \sup_{\mathbf{z}} \left\{ \mathcal{M}_{\mathbf{z}} \right\}$$

Vapnik-Chervonenkis: with (at least) probability $1 - \delta$,

$$\forall m \in \mathcal{M}, \mathcal{R}(m) \leq \widehat{\mathcal{R}}_n(m) + 2\sqrt{\frac{2}{n}[\log G_{\mathcal{M}}(2n) - \log(4\delta)]}$$

The VC (Vapnik-Chervonenkis) dimension is the largest n such that $G_{\mathcal{M}}(n) = 2^n$. It will be denoted VC(\mathcal{M}). Observe that $G_{\mathcal{M}}(n) \leq 2^n$

 $n \leq VC(\mathcal{M}): n \mapsto G_{\mathcal{M}}(n)$ increases exponentially $G_{\mathcal{M}}(n) = 2^n$

$$n \ge \mathrm{VC}(\mathcal{M}): n \mapsto G_{\mathcal{M}}(n) \text{ increases at power speed } G_{\mathcal{M}}(n) \le \left(\frac{en}{\mathrm{VC}(\mathcal{M})}\right)^{\mathrm{VC}(\mathcal{M})}$$

Vapnik-Chervonenkis: with (at least) probability $1 - \delta$,

$$\forall m \in \mathcal{M}, \mathcal{R}(m) \leq \widehat{\mathcal{R}}_n(m) + 2\sqrt{\frac{2}{n}}[\text{VC}(\mathcal{M})\log\left(\frac{en}{\text{VC}(\mathcal{M})}\right) - \log(4\delta)]$$

$\mathcal{R}(m) - \widehat{\mathcal{R}}_n(m)$ - \mathcal{M} infinite

For the worst case scenario $\sup_{m \in \mathcal{M}} \left\{ \mathcal{R}(m) - \widehat{\mathcal{R}}_n(m) \right\} \sim \sqrt{\frac{\text{VC}(\mathcal{M}) \cdot \log n}{n}}$

To go further, see Bousquet, Boucheron & Lugosi (2005, Introduction to Learning Theory)